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RELIABILITY REPORT

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| RELIABILITY DATA LTC5100 / LTC2240 / 2241 / 2242 | | | | | |
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| 8/21/2006 | | | | | |
| • OPERATING LIFE TES | Г | | | | |
| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS ⁽¹⁾ AT +125°C | NUMBER OF ⁽²⁾ FAILURES |
| QFN/DFN | 234 234 | 0408 | 0626 | 234.00 234.00 | 0 0 |
| HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH | | | | | |
| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICF HOURS ⁽⁴⁾ AT +85°C | NUMBER OF FAILURES |
| QFN/DFN | 50 50 | 0408 | 0408 | 168.00 168.00 | 0 0 |
| PRESSURE COOKER TEST AT 15 PSIG, +121°C | | | | | |
| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS | NUMBER OF FAILURES |
| QFN/DFN | 252 252 | 0313 | 0633 | 84.82 84.82 | 0 0 |
| • TEMP CYCLE FROM -65°C to +150°C | | | | | |
| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE CYCLES | NUMBER OF FAILURES |
| QFN/DFN | 279 279 | 0321 | 0544 | 241.11 241.11 | 0 0 |
| • THERMAL SHOCK FROM -65°C to +150°C | | | | | |
| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE CYCLES | NUMBER OF FAILURES |
| QFN/DFN | 281 281 | 0313 | 0544 | 242.50 242.50 | 0 0 |
| (1) Assumes Activation Energy = 0.7 Electron Volts (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 50.58 FITS (3) Mean Time Between Failures in Years = 2,255 (4) Assumes 20X Acceleration from 85°C to +131°C Note: 1 FIT = 1 Failure in One Billion Hours. | | | | | |

Form: 00-03-6209B. R492

Rev 4